



LABORATORY
REG. No. 1149

Parkside Laboratories (Aust)

TEST AND CERTIFICATION SERVICES

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Laboratory Test Report

Report No.: 1272/2

Date Issued: 16 December 2003

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SUBJECT: Cubic switchboard assembly "Cubic Test Panel 1" with various modules types, sizes and protecting devices. For details of module types, sizes and protecting devices refer herein. 415V 50Hz.

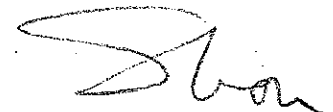
REQUESTED BY: CUBIC Modulsystem A/S
SKJOLDBORGS GADE 21,
DK700 BROENDERSLEV,
DENMARK

INSTRUCTIONS: Standard internal arcing-fault tests with the prospective short-circuit current of 63kA to APPENDIX "ZD" of AS 3439.1-2002
"Low-voltage switchgear and controlgear assemblies
Part 1. Type-tested and partially type-tested assemblies"

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SUMMARY: The tested modules passed the appropriate tests described herein.

NATA APPROVED SIGNATORY: Antony K. Milovac

PREPARED BY: 
Steve Kon
Test Engineer

GENERAL

- a As detailed in this report, three modules specified in DESCRIPTION were tested.
- b The results detailed in this report were based on the sample submitted by the manufacturer with order No. 150356.
- c The test samples were subjected to the relevant clauses as stated herein.
- d Power supplies used were mains derived a.c. voltage sources of substantially sinusoidal waveform with a nominal frequency of 50Hz unless otherwise noted.
- e Dates of high current tests are shown on oscillograms.
- f Note: N/R means Not Relevant, N/T means Not Tested, DNC means Did Not Comply, T.O. means Test Object.

WITNESSES:

Lars Poulson	CUBIC
Jorn Jacobsen	CUBIC
Bill Mairs	NHP
Stephen Barker	NHP

TEST SPECIFICATION

AS/NZS 3439.1:2002

Low-voltage switchgear and controlgear assemblies –
Part 1: Type-tested and partially type-tested assemblies

DATE OF TEST

The testing was performed from 27th to 30th October 2003.